



Automotive **RF** immunity test set-up analysis

Why test results can't compare ...

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ISO 11452-4 (BCI) • ISO 11452-2 (RI) Conclusions

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Introduction

- ISO 11452-4 (BCI) and ISO 11452-2 (RI)
- Lack of reproducibility of test results when set-ups are recreated at different test labs
- Module compliance doesn't necessarily mean in-vehicle compliance after integration
- Compliance to over-testing over a large range has an inverse impact on economics



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Introduction

analysis

- With shorter design cycles and higher reliability requirements, result matching between IC, module and vehicle is preferred
- Only possible when certain requirements are being met













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ISO 11452-2 (RI)

- Cable harness at 50 mm above GRP: \sim 150 Ω
- Cable harness length; 1,5 2 m
- Antennae used; bi-conical log-per, horn E/H field ratio determined by antenna gain
- Closed-loop E-field @ 0,15 m above GRP, 0,1 m from GRP edge, 1 m from antenna front
- Load box CM impedance (undefined)
- ISNs (defined up to 100 MHz, 25 Ω in CM)









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ISO 11452-2 (RI)

- RI test done in 400 1000 MHz range
- H/V polarized antenna
- Cable harness: 2 m @ 50 mm above GRP
- Loadbox CM impedance at 1, 50, 100, 200 Ω and 5k Ω (open circuit)
- Worst case value from transfer taken











ISO 11452-2 (RI)

- Induced CM voltage across 'open' EUT load substantially higher then when loaded with 50 Ω
- Induced CM voltage has little relation with Efield as function of frequency due to resonances
- Induced CM voltages hardly calculable due to 'odd' E-field sensing technique used





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Possible (cor)relation with DPI or other EMC IC test methods

- DPI: 10 V over 50 Ω equals 200mA (max.) DPI applies to pins, BCI to harnesses DPI doesn't simulate resonances like BCI Without resonances DPI more severe than BCI
- TEM cell, 5 W over 50 Ω equals 15,8 V
 15,8 V over 45 mm equals 351 V/m
 10 V over 45 mm equals 222 V/m
 TEM cell exposes device not complete sensor
 TEM cell more severe than RI





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Conclusions

- Present ISO standards not unambiguous:
 - ISN vs CM impedance
 - Loadbox impedances and reference undefined
 - Harness impedance (50 mm \rightarrow 176 Ω in CM)
 - BCI clamps used (different turn ratio)
 - Open-/closed-loop determined by EUT application
 - Antennae used (at too close distance: E/H ratio)
 - E-field sensor's position (motor hood measurements?)
 - E-fields not calculable, H-field ignored (odd calibration)



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Recommendations

- Integrate loadbox with ISN to defined CM impedance; 150 Ω , 100 kHz 400 MHz
- BCI clamp turn ratio becomes irrelevant
- Set-up resonances diminish
- Open-/closed loop determined by EUT grounding
- E-field calibration acc. IEC 61000-4-3, then apply test set-up to field
- Fix harness length e.g. 2 m for all measurements, wide meander (s > h) shall be allowed



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Application recommendations

- Don't RF short-circuit inputs nor outputs directly to ground (by using caps to gnd)
- Apply RF series impedance or better CM impedances towards harness to enforce characteristic termination
- Characteristic harness impedance less than 150 Ω near to metal structures, 50 Ω more appropriate



